

Notice of References Cited

Application/Control No.

10/796,599

Applicant(s)/Patent Under
Reexamination
FENG, WEISHI

Examiner

MARTIN JERIKO P. SAN JUAN

Art Unit

2132

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,683,954 B1	01-2004	Searle, Scott	380/30
*	B	US-7,380,135 B2	05-2008	Nishimoto et al.	713/193
	C	US-			
	D	US-			
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	F	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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